Microsemi Corporation - A1460A-1CQ196M Datasheet

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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	848
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	168
Number of Gates	6000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	196-BCQFP with Tie Bar
Supplier Device Package	196-CQFP (63.5x63.5)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1460a-1cq196m

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Device/Package	Speed Grade[1]				Application[1]			
	Std.	–1	–2	–3	C	I	M	B
A14V40A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
A1460A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–
196-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
207-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
208-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
225-Pin Plastic Ball Grid Array (BGA)	D	D	D	D	D	–	–	–
A14V60A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
208-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A14100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	✓	D	D	✓	✓	–	–
257-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
313-Pin Plastic Ball Grid Array (BGA)	✓	✓	D	D	✓	–	–	–
256-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
A14V100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	–	–	–	✓	–	–	–
313-Pin Plastic Ball Grid Array (BGA)	✓	–	–	–	✓	–	–	–

Notes:

1. *Applications:*
   C = Commercial
   I = Industrial
   M = Military
2. *Commercial only*

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

2 – Detailed Specifications

This section of the datasheet is meant to familiarize the user with the architecture of the ACT 3 family of FPGA devices. A generic description of the family will be presented first, followed by a detailed description of the logic blocks, the routing structure, the antifuses, and the special function circuits. The on-chip circuitry required to program the devices is not covered.

Topology

The ACT 3 family architecture is composed of six key elements: Logic modules, I/O modules, I/O Pad Drivers, Routing Tracks, Clock Networks, and Programming and Test Circuits. The basic structure is similar for all devices in the family, differing only in the number of rows, columns, and I/Os. The array itself consists of alternating rows of modules and channels. The logic modules and channels are in the center of the array; the I/O modules are located along the array periphery. A simplified floor plan is depicted in Figure 2-1.

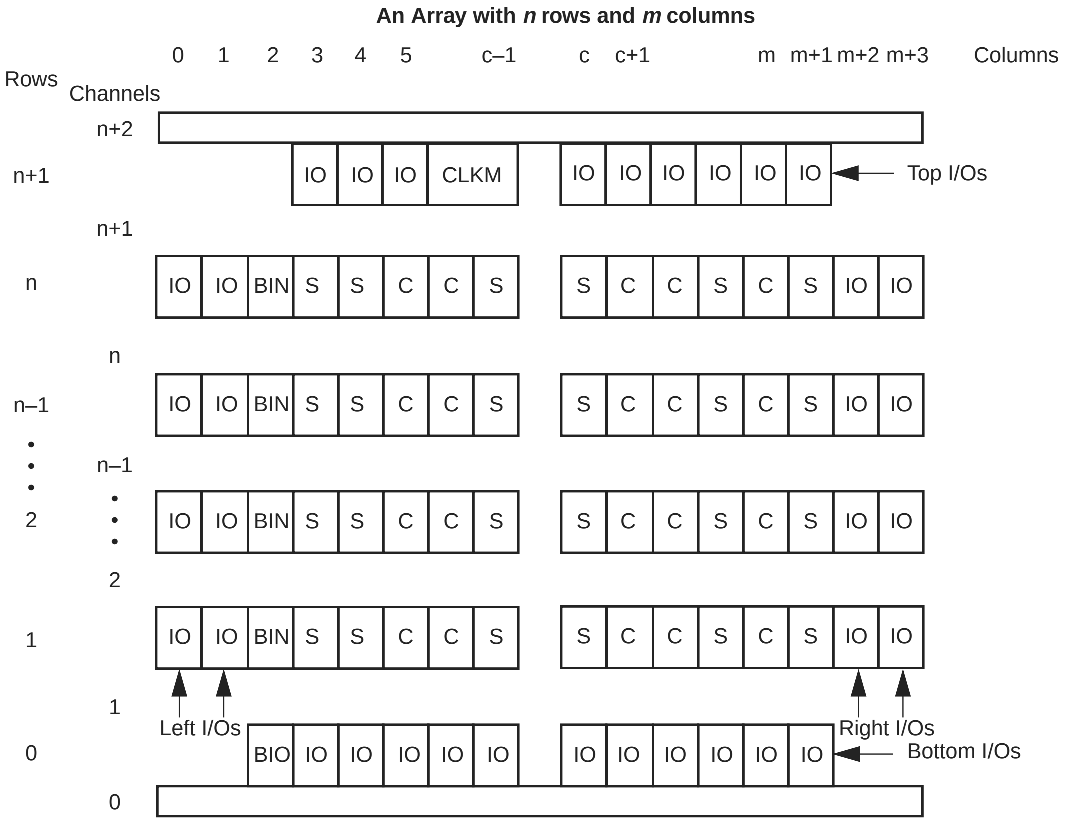


Figure 2-1 • **Generalized Floor Plan of ACT 3 Device**

The I/O module output Y is used to bring Pad signals into the array or to feed the output register back into the array. This allows the output register to be used in high-speed state machine applications. Side I/O modules have a dedicated output segment for Y extending into the routing channels above and below (similar to logic modules). Top/Bottom I/O modules have no dedicated output segment. Signals coming into the chip from the top or bottom are routed using F-fuses and LVTs (F-fuses and LVTs are explained in detail in the routing section).

I/O Pad Drivers

All pad drivers are capable of being tristate. Each buffer connects to an associated I/O module with four signals: OE (Output Enable), IE (Input Enable), DataOut, and DataIn. Certain special signals used only during programming and test also connect to the pad drivers: OUTEN (global output enable), INEN (global input enable), and SLEW (individual slew selection). See Figure 2-5.

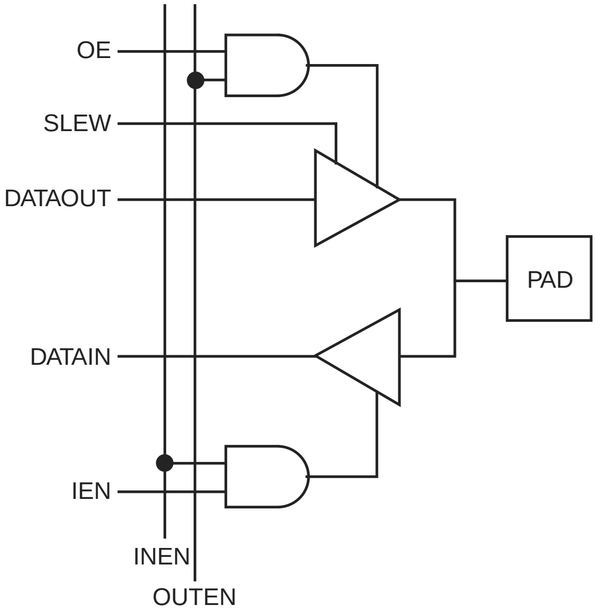


Figure 2-5 • **Function Diagram for I/O Pad Driver**

Special I/Os

The special I/Os are of two types: temporary and permanent. Temporary special I/Os are used during programming and testing. They function as normal I/Os when the MODE pin is inactive. Permanent special I/Os are user programmed as either normal I/Os or special I/Os. Their function does not change once the device has been programmed. The permanent special I/Os consist of the array clock input buffers (CLKA and CLKB), the hard-wired array clock input buffer (HCLK), the hard-wired I/O clock input buffer (IOCLK), and the hard-wired I/O register preset/clear input buffer (IOPCL). Their function is determined by the I/O macros selected.

Clock Networks

The ACT 3 architecture contains four clock networks: two high-performance dedicated clock networks and two general purpose routed networks. The high-performance networks function up to 200 MHz, while the general purpose routed networks function up to 150 MHz.

Module Output Connections

Module outputs have dedicated output segments. Output segments extend vertically two channels above and two channels below, except at the top or bottom of the array. Output segments twist, as shown in Figure 10, so that only four vertical tracks are required.

LVT Connections

Outputs may also connect to nondedicated segments called Long Vertical Tracks (LVTs). Each module pair in the array shares four LVTs that span the length of the column. Any module in the column pair can connect to one of the LVTs in the column using an FF connection. The FF connection uses antifuses connected directly to the driver stage of the module output, bypassing the isolation transistor. FF antifuses are programmed at a higher current level than HF, VF, or XF antifuses to produce a lower resistance value.

Antifuse Connections

In general every intersection of a vertical segment and a horizontal segment contains an unprogrammed antifuse (XF-type). One exception is in the case of the clock networks.

Clock Connections

To minimize loading on the clock networks, a subset of inputs has antifuses on the clock tracks. Only a few of the C-module and S-module inputs can be connected to the clock networks. To further reduce loading on the clock network, only a subset of the horizontal routing tracks can connect to the clock inputs of the S-module.

Programming and Test Circuits

The array of logic and I/O modules is surrounded by test and programming circuits controlled by the temporary special I/O pins MODE, SDI, and DCLK. The function of these pins is similar to all ACT family devices. The ACT 3 family also includes support for two Actionprobe® circuits, allowing complete observability of any logic or I/O module in the array using the temporary special I/O pins, PRA and PRB.

3.3 V Operating Conditions

***Table 2-5* • Absolute Maximum Ratings[1], Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.*

***Table 2-6* • Recommended Operating Conditions**

Parameter	Commercial	Units
Temperature range*	0 to +70	°C
Power supply tolerance	3.0 to 3.6	V

*Note: *Ambient temperature (T_A) is used for commercial.*

***Table 2-7* • Electrical Specifications**

Parameter		Commercial		Units
		Min.	Max.	
VOH[1]	IOH = –4 mA	2.15	–	V
	IOH = –3.2 mA	2.4		V
VOL[1]	IOL = 6 mA		0.4	V
VIL		–0.3	0.8	V
VIH		2.0	VCC + 0.3	V
Input transition time t_R, t_F[2]	VI = VCC or GND	–10	+10	µA
C_{IO} I/O Capacitance[2,3]			10	pF
Standby current, ICC[4] (typical = 0.3 mA)			0.75	mA
Leakage current[5]		–10	10	µA

1. *Only one output tested at a time. VCC = minimum.*
2. *Not tested; for information only.*
3. *Includes worst-case 84-pin PLCC package capacitance. VOUT = 0 V, f - 1 MHz.*
4. *Typical standby current = 0.3 mA. All outputs unloaded. All inputs = VCC or GND.*
5. *VO, VIN = VCC or GND*

Power Dissipation

$$P = [ICC\ standby + Iactive] * VCC * IOL * VOL * N + IOH* (VCC - VOH) * M$$

EQ 3

where:

ICC standby is the current flowing when no inputs or outputs are changing

Iactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source current.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M equals the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the design and on the system I/O. The power can be divided into two components: static and active.

Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in Table 2-9 for commercial, worst case conditions.

***Table 2-9* • Standby Power Calculation**

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by EQ 4.

$$\text{Power } (\mu W) = C_{EQ} * VCC^2 * F$$

EQ 4

Where:

C_{EQ} is the equivalent capacitance expressed in pF.

VCC is the power supply in volts.

F is the switching frequency in MHz.

Tightest Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer lengths of routing track. The ACT 3 family delivers the tightest fanout delay distribution of any FPGA. This tight distribution is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented PLICE antifuse offers a very low resistive/capacitive interconnect. The ACT 3 family's antifuses, fabricated in 0.8 micron m lithography, offer nominal levels of 200Ω resistance and 6 femtofarad (fF) capacitance per antifuse. The ACT 3 fanout distribution is also tighter than alternative devices due to the low number of antifuses required per interconnect path. The ACT 3 family's proprietary architecture limits the number of antifuses per path to only four, with 90% of interconnects using only two antifuses.

The ACT 3 family's tight fanout delay distribution offers an FPGA design environment in which fanout can be traded for the increased performance of reduced logic level designs. This also simplifies performance estimates when designing with ACT 3 devices.

Table 2-14 **• Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions**

Speed Grade	**FO = 1**	**FO = 2**	**FO = 3**	**FO = 4**	**FO = 8**
ACT 3 –3	2.9	3.2	3.4	3.7	4.8
ACT 3 –2	3.3	3.7	3.9	4.2	5.5
ACT 3 –1	3.7	4.2	4.4	4.8	6.2
ACT 3 STD	4.3	4.8	5.1	5.5	7.2

Notes:

1. *Obtained by added $t_{RD(x=FO)}$ to t_{PD} from the Logic Module Timing Characteristics Tables found in this datasheet.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

Timing Characteristics

Timing characteristics for ACT 3 devices fall into three categories: family dependent, device dependent, and design dependent. The input and output buffer characteristics are common to all ACT 3 family members. Internal routing delays are device dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design is complete. Delay values may then be determined by using the ALS Timer utility or performing simulation with post-layout delays.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most time-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6% of the nets in a design may be designated as critical, while 90% of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections. This increases capacitance and resistance, result ng in longer net delays for macros connected to long tracks. Typically up to 6% of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 14 ns delay. This additional delay is represented statistically in higher fanout (FO = 8) routing delays in the datasheet specifications section.

A1415A, A14V15A Timing Characteristics (continued)

***Table 2-21* • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

Dedicated (hardwired) I/O Clock Network		**–3 Speed**		**–2 Speed**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{IOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t_{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t_{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t_{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t_{IOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t_{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f_{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t_{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t_{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t_{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t_{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t_{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t_{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f_{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t_{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t_{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t_{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t_{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t_{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f_{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
$t_{IOHCKSW}$	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
$t_{IORCKSW}$	I/O Clock to R-Clock Skew (FO = 64)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
t_{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 50% maximum)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0 0.0	3.0 3.0	ns

Notes:

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A1460A, A14V60A Timing Characteristics (continued)

***Table 2-31* • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.3		1.5		1.8		2.0		2.0		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

5. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
6. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

SDO Serial Data Output (Output)

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

DCLK Diagnostic Clock (Input)

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

VCC 5 V Supply Voltage

HIGH supply voltage.

PQ160			
Pin Number	**A1425, A14V25 Function**	**A1440, A14V40 Function**	**A1460, A14V60 Function**
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
5	NC	I/O	I/O
9	MODE	MODE	MODE
10	VCC	VCC	VCC
14	NC	I/O	I/O
15	GND	GND	GND
18	VCC	VCC	VCC
19	GND	GND	GND
20	NC	I/O	I/O
24	NC	I/O	I/O
27	NC	I/O	I/O
28	VCC	VCC	VCC
29	VCC	VCC	VCC
40	GND	GND	GND
41	NC	I/O	I/O
43	NC	I/O	I/O
45	NC	I/O	I/O
46	VCC	VCC	VCC
47	NC	I/O	I/O
49	NC	I/O	I/O
51	NC	I/O	I/O
53	NC	I/O	I/O
58	PRB, I/O	PRB, I/O	PRB, I/O
59	GND	GND	GND
60	VCC	VCC	VCC
62	HCLK, I/O	HCLK, I/O	HCLK, I/O
63	GND	GND	GND
74	NC	I/O	I/O
75	VCC	VCC	VCC
76	NC	I/O	I/O
77	NC	I/O	I/O
78	NC	I/O	I/O
79	SDO	SDO	SDO
80	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
81	GND	GND	GND
90	VCC	VCC	VCC
91	VCC	VCC	VCC

PQ160			
Pin Number	**A1425, A14V25 Function**	**A1440, A14V40 Function**	**A1460, A14V60 Function**
92	NC	I/O	I/O
93	NC	I/O	I/O
98	GND	GND	GND
99	VCC	VCC	VCC
100	NC	I/O	I/O
103	GND	GND	GND
107	NC	I/O	I/O
109	NC	I/O	I/O
110	VCC	VCC	VCC
111	GND	GND	GND
112	VCC	VCC	VCC
113	NC	I/O	I/O
119	NC	I/O	I/O
120	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
121	GND	GND	GND
124	NC	I/O	I/O
127	NC	I/O	I/O
136	CLKA, I/O	CLKA, I/O	CLKA, I/O
137	CLKB, I/O	CLKB, I/O	CLKB, I/O
138	VCC	VCC	VCC
139	GND	GND	GND
140	VCC	VCC	VCC
141	GND	GND	GND
142	PRA, I/O	PRA, I/O	PRA, I/O
143	NC	I/O	I/O
145	NC	I/O	I/O
147	NC	I/O	I/O
149	NC	I/O	I/O
151	NC	I/O	I/O
153	NC	I/O	I/O
154	VCC	VCC	VCC
160	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

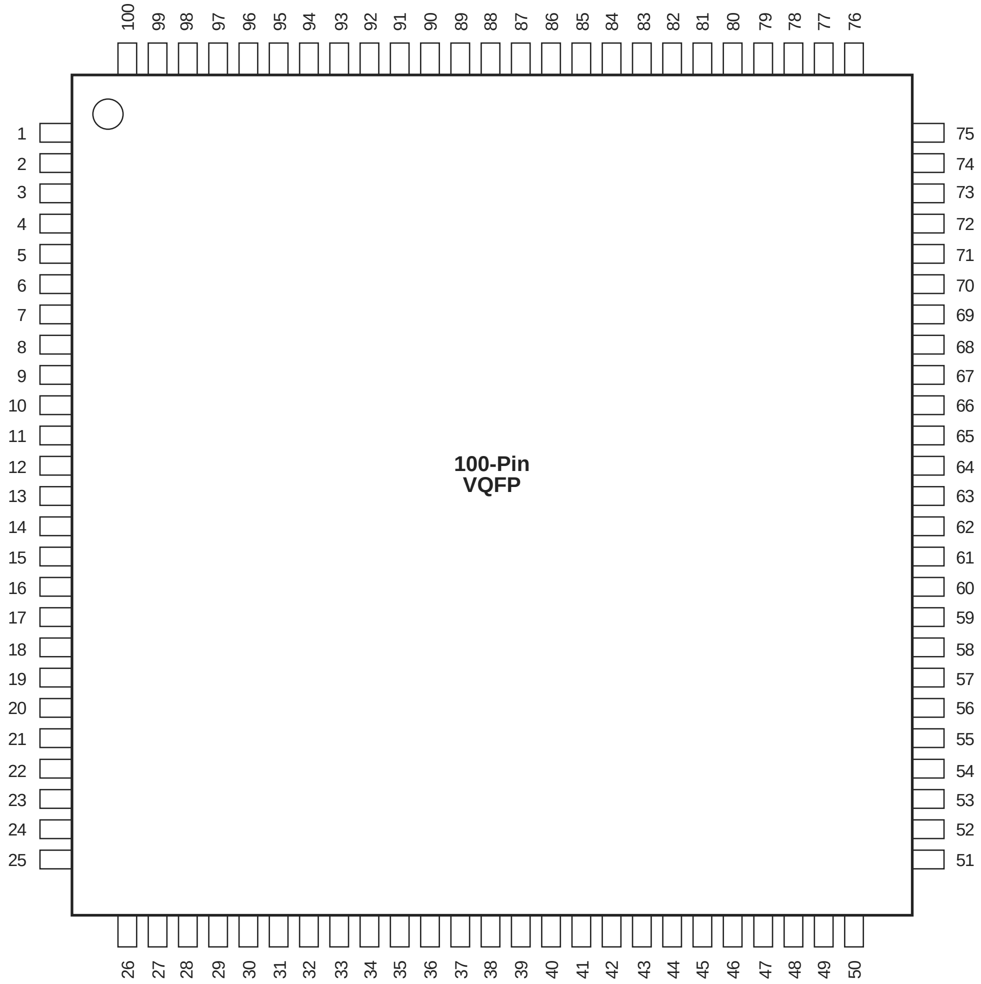
1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PQ208, RQ208		
Pin Number	**A1460, A14V60 Function**	**A14100, A14V100 Function**
1	GND	GND
2	SDI, I/O	SDI, I/O
11	MODE	MODE
12	VCC	VCC
25	VCC	VCC
26	GND	GND
27	VCC	VCC
28	GND	GND
40	VCC	VCC
41	VCC	VCC
52	GND	GND
53	NC	I/O
60	VCC	VCC
65	NC	I/O
76	PRB, I/O	PRB, I/O
77	GND	GND
78	VCC	VCC
79	GND	GND
80	VCC	VCC
82	HCLK, I/O	HCLK, I/O
98	VCC	VCC
102	NC	I/O
103	SDO	SDO
104	IOPCL, I/O	IOPCL, I/O
105	GND	GND
114	VCC	VCC
115	VCC	VCC
116	NC	I/O
129	GND	GND
130	VCC	VCC
131	GND	GND
132	VCC	VCC
145	VCC	VCC
146	GND	GND
147	NC	I/O
148	VCC	VCC
156	IOCLK, I/O	IOCLK, I/O
157	GND	GND
158	NC	I/O
164	VCC	VCC
180	CLKA, I/O	CLKA, I/O
181	CLKB, I/O	CLKB, I/O
182	VCC	VCC
183	GND	GND
184	VCC	VCC
185	GND	GND
186	PRA, I/O	PRA, I/O
195	NC	I/O
201	VCC	VCC
205	NC	I/O
208	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

VQ100

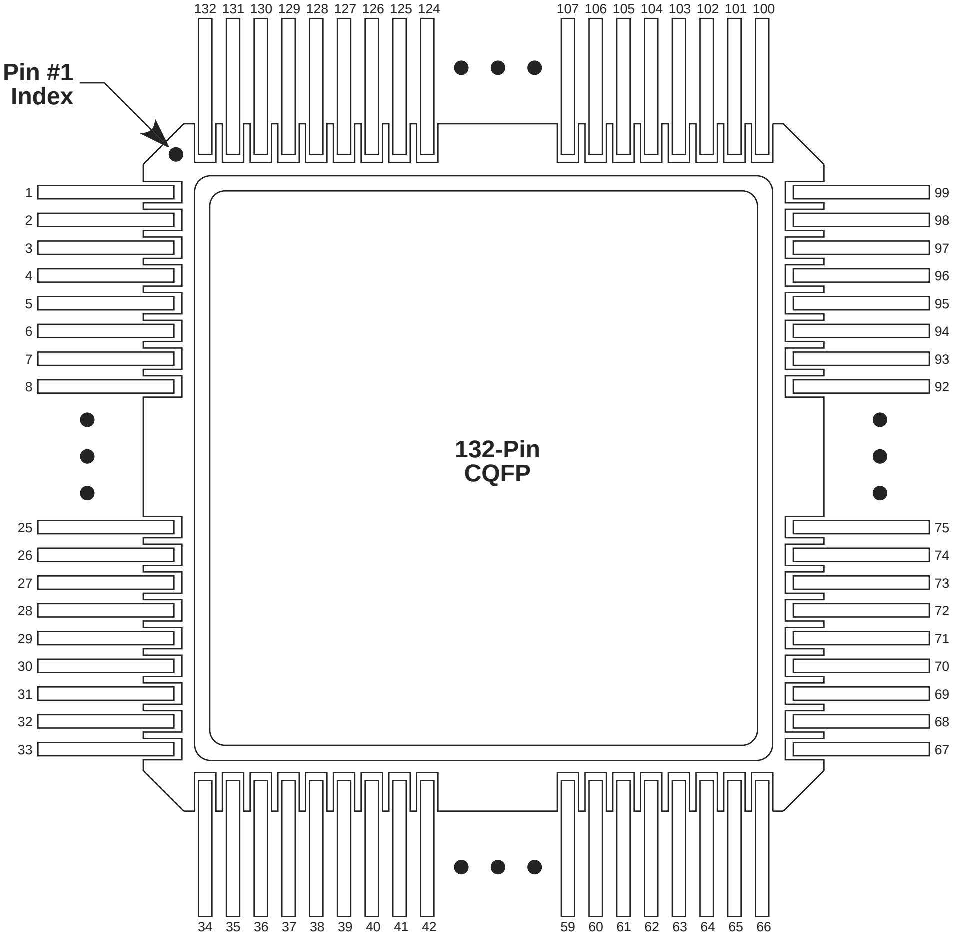


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

CQ132



Note: This is the top view

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

BG225	
A1460 Function	**Location**
CLKA or I/O	C8
CLKB or I/O	B8
DCLK or I/O	B2
GND	A1, A15, D15, F8, G7, G8, G9, H6, H7, H8, H9, H10, J7, J8, J9, K8, P2, R15
HCLK or I/O	P9
IOCLK or I/O	B14
IOPCL or I/O	P14
MODE	D1
NC	A11, B5, B7, D8, D12, F6, F11, H1, H12, H14, K11, L1, L13, N8, P5, R1, R8, R11, R14
PRA or I/O	A7
PRB or I/O	L7
SDI or I/O	D4
SDO	N13
VCC	A8, B12, D5, D14, E3, E8, E13, H2, H3, H11, H15, K4, L2, L12, M8, M15, P4, P8, R13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The BG225 package has been discontinued.

BG313	
A14100, A14V100 Function	**Location**
CLKA or I/O	J13
CLKB or I/O	G13
DCLK or I/O	B2
GND	A1, A25, AD2, AE25, J21, L13, M12, M14, N11, N13, N15, P12, P14, R13
HCLK or I/O	T14
IOCLK or I/O	B24
IOPCL or I/O	AD24
MODE	G3
NC	A3, A13, A23, AA5, AA9, AA23, AB2, AB4, AB20, AC13, AC25, AD22, AE1, AE21, B14, C5, C25, D4, D24, E3, E21, F6, F10, F16, G1, G25, H18, H24, J1, J7, J25, K12, L15, L17, M6, N1, N5, N7, N21, N23, P20, R11, T6, T8, U9, U13, U21, V16, W7, Y20, Y24
PRA or I/O	H12
PRB or I/O	AD12
SDI or I/O	C1
SDO	AE23
VCC	AB18, AD6, AE13, C13, C19, E13, G9, H22, K8, K20, M16, N3, N9, N25, U5, W13, V2, V22, V24

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG175	
A1440 Function	**Location**
CLKA or I/O	C9
CLKB or I/O	A9
DCLK or I/O	D5
GND	D4, D8, D11, D12, E4, E14, H4, H12, L4, L12, M4, M8, M12
HCLK or I/O	R8
IOCLK or I/O	E12
IOPCL or I/O	P13
MODE	F3
NC	A1, A2, A15, B2, B3, P2, P14, R1, R2, R14, R15
PRA or I/O	B8
PRB or I/O	R7
SDI or I/O	D3
SDO	N12
VCC	C3, C8, C13, E15, H3, H13, L1, L14, N3, N8, N13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG175 package has been discontinued.

PG207	
A1460 Function	**Location**
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.